Issue Classification	ation	Application/Control No.	Applicant(s)/P. BASU ET AL.	Applicant(s)/Patent under Reexamination BASU ET AL.	ion
		Examiner Nguyen, Toan D	Art Unit 2616		
	ORIGINAL		INTERNATIONAL	INTERNATIONAL CLASSIFICATION	Z
CLASS		SUBCLASS	CLAIMED	NON-CLAIMED	IMED
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CROS	CROSS REFERENCE(S)	E(S)			
CLASS SUBCI	SUBCLASS (ONE SUBCLASS	CLASS PER BLOCK)			
370 252	254				
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Toan Nguyen (Assistant Examiner)	10/12/06 (Date)	HUY D. VU SUPERVISORY PATENT EXAMINER TECHNOLOGY CENTER 2600	NER 0	Total Claims Allowed:	Allowed:
Marcia Yallan (Legal Instruments Examiner)	1812 10/17/06	(Primary Examiner)	(Date) 10/13/06	O.G. Print Claim(s)	O.G. Print Figure 1

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